Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/657,488	CHEN, WEI-BIN	
Examiner	Art Unit	
José V. Chen	3637	

		<u>.</u>		
SEARCHED				
Class	Subclass	Date	Examiner	
18	513 541	8/3/18	110	
	55el			
	53,3			
204	1			
	335			
		:		
		į, į		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
		:		
		;		

		DATE	EXMR
For g ba	ex Co.	8/3/05	14
,			
:			
•			
:	:		
	:		•
	i		
9			
:			
:			